

FORM PTO-1449	U. S DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO.	SERIAL NO.
<p style="text-align: center;">INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)</p>		U 015152-6	10/823,990
		APPLICANT	
		Chia Gee WANG et al.	
		FILING DATE	GROUP
		April 14, 2004	2811 2818

REFERENCE DESIGNATION		U.S. PATENT DOCUMENTS			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	FILING DATE IF APPROPRIATE
Al	AA	6,376,337	04/02	Wang et al.	
Al	AB	6,294,802	09/01	Unoza	
Al	AC	6,355,951	03/02	Hattori	
Al	AD	6,479,836	11/02	Suzuki et al.	
Al	AE	6,452,206	09/02	Harman et al.	
Al	AF	6,537,911	03/03	Ko et al.	
Al	AG	4,261,771	04/1981	Dingle et al.	
	AH				
	AI				

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
				YES	NO
	AJ				
	AK				
	AL				
	AM				

## OTHER ART (Including Author, Title, Date, Pertinent Dates, Etc.)

Al	AN	Tsu, R. "Phenomena in silicon nanostructure devices", <i>Applied Physics A</i> (2000), 71: 391-402
Al	AO	Tsu, Raphael et al. "Quantum Confinement in Silicon", <i>Proceedings of the Fourth International Symposium on Quantum Confinement: Nanoscale Materials, Devices, and Systems</i> , Volume 97-11. Cahay, M. et al. Editors. New Jersey: The Electrochemical Society, Inc. 341-351
Al	AP	Ding, Jinli and Raphael Tsu. "The determination of activation energy in quantum wells", <i>Appl. Phys. Lett.</i> (1997), 71(15): 2124-2126
Al	AQ	Seo, Yong-Jin and Raphael Tsu. "Electronic and Optical Characteristics of Multilayer Nanocrystalline Silicon/Adsorbed Oxygen Superlattice", <i>Jpn. J. Appl. Phys.</i> (2001), 40: 4799-4801
Al	AR	Seo, Yong-Jin et al. "Transport through a nine period silicon/oxygen superlattice", <i>Applied Physics Letters</i> (2001), 79(6): 788-790

EXAMINER

*Andy May*

DATE CONSIDERED

*10/28/05*

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.